## Search Notes



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Examiner

HENOK G HEYI

10524444

Applicant(s)/Patent Under Reexamination

MOCHIZUKI ET AL.

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## SEARCHED Class Subclass Date Examiner 369 47.1 05/05/2008 Henok Heyi 53.1 05/05/2008 Henok Heyi 53.2 Henok Heyi 05/05/2008 53.41 05/05/2008 Henok Heyi

SEARCH NOTES			
Search Notes	Date	Examiner	
Searched EAST and refered to International Search Report (ISR).	05/05/2008	Henok Heyi	

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
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